



<b>PCN Number:</b>	20231130001.1		<b>PCN Date:</b>	December 04, 2023	
<b>Title:</b>	Qualification of UMC-F12 as an additional Fab site option and TI Clark as an additional Assembly site for select devices				
<b>Customer Contact:</b>	Change Management Team		<b>Dept:</b>	Quality Services	
<b>Proposed 1<sup>st</sup> Ship Date:</b>	Mar 4, 2024		<b>Sample requests accepted until:</b>	Jan 4, 2024*	
<b>*Sample requests received after Jan 04, 2024 will not be supported.</b>					
<b>Change Type:</b>					
<input checked="" type="checkbox"/>	Assembly Site	<input type="checkbox"/>	Design	<input type="checkbox"/>	Wafer Bump Material
<input type="checkbox"/>	Assembly Process	<input type="checkbox"/>	Data Sheet	<input type="checkbox"/>	Wafer Bump Process
<input type="checkbox"/>	Assembly Materials	<input type="checkbox"/>	Part number change	<input checked="" type="checkbox"/>	Wafer Fab Site
<input type="checkbox"/>	Mechanical Specification	<input type="checkbox"/>	Test Site	<input type="checkbox"/>	Wafer Fab Material
<input type="checkbox"/>	Packing/Shipping/Labeling	<input type="checkbox"/>	Test Process	<input type="checkbox"/>	Wafer Fab Process
<b>PCN Details</b>					
<b>Description of Change:</b>					
Texas Instruments is pleased to announce the qualification of its UMC-F12 fabrication facility as an additional Wafer Fab option and TI Clark as an additional Assembly site.					
<b>Current Fab Site</b>			<b>New Fab Site</b>		
<b>Current Fab Site</b>	<b>Process</b>	<b>Wafer Diameter</b>	<b>New Fab Site</b>	<b>Process</b>	<b>Wafer Diameter</b>
RFAB	LBC9	300 mm	UMC-F12	LBC9	300 mm
<b>Material Differences:</b>					
No material differences between Assembly sites.					
<b>Reason for Change:</b>					
Supply Continuity					
<b>Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):</b>					
None					
<b>Impact on Environmental Ratings</b>					
Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental ratings.					
<b>RoHS</b>		<b>REACH</b>		<b>Green Status</b>	
<input checked="" type="checkbox"/> No Change		<input checked="" type="checkbox"/> No Change		<input checked="" type="checkbox"/> No Change	
				<b>IEC 62474</b>	
				<input checked="" type="checkbox"/> No Change	
<b>Changes to product identification resulting from this PCN:</b>					
<b>Fab Site Information:</b>					
Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City		
RFAB	RFB	USA	Richardson		
<b>UMC-F12</b>	<b>F12</b>	<b>TWN</b>	<b>Tainan</b>		
<b>Assembly Site Information:</b>					
Assembly Site	Assembly Site Origin (22L)	Assembly Country Code (23L)	Assembly City		
TI Chengdu	CDA	CHN	Chengdu		
<b>TI Clark</b>	<b>QAB</b>	<b>PHL</b>	<b>Angeles City, Pampanga</b>		
Sample product shipping label (not actual product label):					

 <b>TEXAS INSTRUMENTS</b> MADE IN: Malaysia 2DC: 29: MSL '2 /260C/1 YEAR SEAL DT MSL 1 /235C/UNLIM 03/29/04 OPT: ITEM: 39 <b>LBL: 5A (L)T0:1750</b>		(1P) SN74LS07NSR (Q) 2000 (D) 0336 (31T) LOT: 3959047MLA (4W) TKY (1T) 7523483SI2 (P) (2P) REV: (V) 0033317 (20L) CSO: SHE (21L) CCO:USA (22L) ASO: MLA (23L) ACO: MYS
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<b>Product Affected:</b>		
BQ24179YBGR	BQ25790YBGR	BQ25790YBGT

## Qualification Report

Approve Date 16-FEBRUARY-2022

### Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: BQ25790YBG	QBS Process/Package Reference: BQ25960YBG	QBS Process Reference: BQ25980YFF
-	Bump-shear (WCSP)	min 50 bumps	-	3/150/0	-
-	Manufacturability TQ - Testability	(per mfg. Site specification)	1/Pass	1/Pass	1/Pass
CDM	ESD - CDM	750 V	-	-	1/3/0
CDM	ESD - CDM	1500 V	1/3/0	1/3/0	-
ED	Electrical Characterization	Per Datasheet Parameters	1/30/0	1/30/0	1/30/0
HAST	Biased HAST, 130C/85%RH	96 hours		3/231/0	3/231/0
HBM	ESD - HBM	4000 V	1/3/0	1/3/0	1/3/0
HTOL	Life Test, 125C	1000 hours	1/77/0	1/77/0	1/77/0
HTSL	High Temp Storage Bake 150C	1000 hours	1/77/0	3/231/0	3/231/0
LU	Latch-up	(per JESD78 ), Ta=Room, high	1/6/0	1/6/0	1/6/0
MQ	Manufacturability (Assembly)	(per mfg. Site specification)	1/Pass	1/Pass	3/Pass
MQ	Manufacturability (Bump)	(per mfg. Site specification)	-	1/Pass	1/Pass
TC	Temperature Cycle, -55/125C	700 cycles	-	3/231/0	3/231/0
UHAST	Unbiased HAST 130C/85%RH	96 hours	-	3/231/0	3/231/0

QBS: Qual By Similarity

Qual Device BQ25790YBG is qualified at LEVEL1-260C

Qual Device BQ24179YBG is qualified at LEVEL1-260C. BQ24179YBG is a paper spin of BQ25790YBG. The only difference between those devices is the top marking.

Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

#### Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the Change Management team or your local Field Sales Representative.

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